

3.3 V 差分多点低电压 M-LVDS 驱动器接收器

UM3400S8 SOP8
UM3401S8 SOP8

描述

UM340XS8系列为纯3.3V电源差分多点低电压(M-LVDS)线路驱动器和接收器。UM3400S8和UM3401S8器件均符合TIA/EIA-899标准。UM3400S8在0.0V下提供1型接收器阈值。UM3401S8在0.1 V下提供2型接收器阈值。

这些器件具有1型和2型接收器，能够在-1V至3.4 V的共模电压范围内，以低至50mV的差分输入电压来检测总线状态。1型接收器具有接近零的阈值(± 50 mV)，并具有25mV 的差分输入电压迟滞，以防止在信号缓慢变化或输入丢失时出现输出振荡。2型接收器具有一个偏移阈值，可在开路、闲置总线和其他故障条件下提供可检测电压。UM3400S8和UM3401S8支持单工或半双工总线配置。

应用

- 低功耗、高速和短行程可替代TIA/EIA-485
- 背板或电缆连接的多点数据和时钟传输
- 蜂窝基站
- 局端交换机
- 网络交换机和路由器

特性

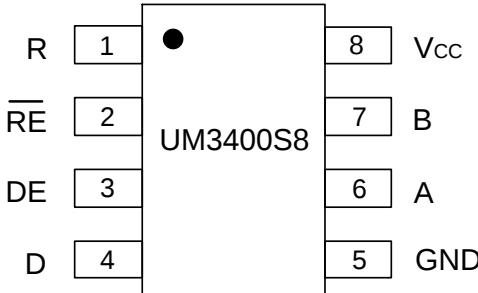
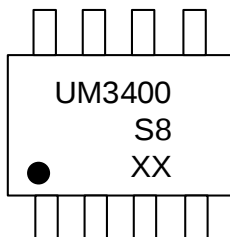
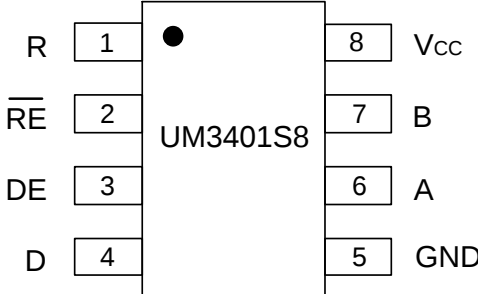
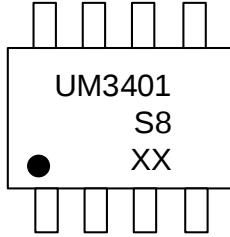
- 低压差分30 Ω 至55 Ω 线路驱动器和接收器，信号传输速率高达100Mbps
- 1型接收器具有25mV的迟滞
- 2型接收器具有100mV偏移阈值来检测开路和空闲总线条件
- 符合或超过M-LVDS标准TIA/EIA – 899, 适用于多点数据交换
- 可控的驱动器输出电压转换时间，提高信号质量
- -1V至3.4V共模电压范围，允许在2V接地噪声下进行数据传输
- 总线引脚在禁用或 $V_{CC} \leq 1.5V$ 时具有高阻抗
- M-LVDS总线上的无毛刺上电/关断
- V_{CC} 电压范围: $V_{CC} = 3.3 \pm 10\% V$ (3.0 至 3.6V)
- 工作环境温度范围: -40 $^{\circ}C$ 至85 $^{\circ}C$
- 闩锁性能 (Latch-up) 超过200mA
- 无铅封装

Ordering Information

Part Number	Temp. Range	Marking Code	Package Type	Shipping Qty
UM3400S8	-40 ℃ to +85 ℃	UM3400S8	SOP8	3000pcs/13Inch Tape & Reel
UM3401S8	-40 ℃ to +85 ℃	UM3401S8	SOP8	3000pcs/13Inch Tape & Reel

Pin Configurations

Top View

 Pin configuration for UM3400S8: - Pin 1: R - Pin 2: $\overline{RE}$ - Pin 3: DE - Pin 4: D - Pin 5: GND - Pin 6: A - Pin 7: B - Pin 8: V_{CC}	 XX: Week Code UM3400S8 SOP8
 Pin configuration for UM3401S8: - Pin 1: R - Pin 2: $\overline{RE}$ - Pin 3: DE - Pin 4: D - Pin 5: GND - Pin 6: A - Pin 7: B - Pin 8: V_{CC}	 XX: Week Code UM3401S8 SOP8

Pin Description

Number	Name	I/O Type	Open Default	Function
1	R	LVC MOS Output		Receiver Output Pin
2	$\overline{\text{RE}}$	LVC MOS Input	HIGH	Receiver Enable Input Pin (LOW = Active, HIGH = High Z Output)
3	DE	LVC MOS Input	LOW	Driver Enable Input Pin (LOW = High Z Output, HIGH=Active)
4	D	LVC MOS Input		Driver Input Pin
5	GND			Ground Supply pin. Pin must be connected to power supply to guarantee proper operation.
6	A	M-LVDS Input/Output		Transceiver True Input /Output Pin
7	B	M-LVDS Input/Output		Transceiver Invert Input /Output Pin
8	V _{CC}			Power Supply pin. Pin must be connected to power supply to guarantee proper operation.

Absolute Maximum Ratings (Note1, 2)

Symbol	Parameter		Value	Unit
V _{CC}	Supply Voltage		-0.3 to 4.0	V
V _{IN}	Input Voltage	D, DE, $\overline{\text{RE}}$	-0.3 to 4.0	V
		A, B (3400, 3401)	-1.8 to 4.0	
V _{OUT}	Output Voltage	R	-0.3 to V _{CC} +0.3	V
		A, B	-1.8 to 4.0	
T _A	Operating Temperature Range, Industrial		-40 to 85	°C
T _{stg}	Storage Temperature Range		-65 to 150	°C

Note1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

Note2: Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and not valid simultaneously. If stress limits are exceeded device functional operation is not implied, damage may occur and reliability may be affected.

Thermal Characteristics

Symbol	Thermal Metric	Value	Unit
θ_{JA}	Junction-to-ambient thermal resistance	110	°C/W
θ_{JC}	Junction-to-case thermal resistance	54	

Electrical Characteristics (Static)

$V_{CC} = 3.3 \pm 10\% V$ (3.0 to 3.6V), $GND = 0 V$, $T_A = -40^{\circ}C$ to $+85^{\circ}C$ (See Notes 1, 2, 3)

Symbol	Parameter		Min	Typ	Max	Unit
I _{CC}	Power Supply Current	Receiver Disabled and Driver Enabled. $\overline{RE}$ and DE at V _{CC} ; R _L = 50 Ω; All others open		13	22	mA
		Driver and Receiver Disabled. $\overline{RE}$ at V _{CC} ; DE at 0 V; R _L = No Load; All others open		1	4	
		Driver and Receiver Enabled. $\overline{RE}$ at 0 V; DE at V _{CC} ; R _L = 50 Ω,; All others open		16	24	
		Receiver Enabled and Driver Disabled. $\overline{RE}$ at 0v; DE at 0 V; R _L = 50 Ω; All others open			13	
V _{IH}	Input HIGH Voltage		2		V _{CC}	V
V _{IL}	Input LOW Voltage		GND		0.8	V
V _{BUS}	Voltage at any bus terminal V _A , V _B		-1.4		3.8	V
V _{ID}	Magnitude of differential input voltage		0.05		V _{CC}	V
Driver						
V _{AB}	Differential output voltage magnitude (see Figure 2)		480		650	mV
Δ V _{AB}	Change in Differential output voltage magnitude between logic states (see Figure 2)		-50		50	mV
V _{OS(SS)}	Steady state common mode output voltage (see Figure 3)		0.8		1.2	V
ΔV _{OS(SS)}	Change in Steady state common mode output voltage between logic states (see Figure 3)		-50		50	mV
V _{OS(PP)}	Peak-to-peak common-mode output voltage (see Figure 3)				150	mV
V _{AOC}	Maximum steady-state open-circuit output voltage (see Figure 7)		0		2.4	V
V _{BOC}	Maximum steady-state open-circuit output voltage (see Figure 7)		0		2.4	V
V _{P(H)}	Voltage overshoot, low-to-high level output (see Figure 5)				1.2V _{SS}	V
V _{P(L)}	Voltage overshoot, high-to-low level output (see Figure 5)		-0.2V _{SS}			V
I _{IH}	High-level input current (D, DE) V _{IH} = 2 V		0		10	μA
I _{IL}	Low-level input current (D, DE) V _{IL} = 0.8 V		0		10	μA
I _{OS}	Differential short-circuit output current magnitude (see Figure 4)				24	mA

Electrical Characteristics (Static) — continued

$V_{CC} = 3.3 \pm 10\%V$ (3.0 to 3.6V), $GND = 0V$, $T_A = -40^\circ C$ to $+85^\circ C$ (See Notes 1, 2, 3)

Receiver					
Symbol	Parameter	Min	Typ	Max	Unit
V_{IT+}	Positive-going Differential Input voltage Threshold (See Figure 9 & Tables 1 and 2)	Type1		50	mV
		Type2		150	
V_{IT-}	Negative-going Differential Input voltage Threshold (See Figure 9 & Tables 1 and 2)	Type1	-50		mV
		Type2	50		
V_{HYS}	Differential Input Voltage Hysteresis (See Figure 9)	Type1		25	mV
		Type2		0	
V_{OH}	High-level output voltage ($I_{OH} = -8mA$)	2.4			V
V_{OL}	Low-level output voltage ($I_{OH} = 8mA$)			0.4	V
I_{IH}	$\overline{RE}$ High-level input current ($V_{IH} = 2V$)	-10		0	μA
I_{IL}	$\overline{RE}$ Low-level input current ($V_{IL} = 0.8V$)	-10		0	μA
I_{OZ}	High-impedance state output current ($V_O = 0V$ or $3.6V$)	-10		15	μA
C_A/C_B	Input Capacitance $V_I = 0.4 \sin(30E^6\pi t) + 0.5V$, other outputs at 1.2V using HP4194A impedance analyzer (or equivalent)		3		pF
C_{AB}	Differential Input Capacitance $V_{AB} = 0.4 \sin(30E^6\pi t)V$, other outputs at 1.2V using HP4194A impedance analyzer (or equivalent)			2.5	pF
$C_{A/B}$	Input Capacitance Balance, (C_A/C_B)	99		101	%
Bus Input and Output					
I_A	Input Current Receiver or Transceiver with Driver Disabled	$V_A=3.8V, V_B=1.2V$	0	32	μA
		$V_A=0V$ or $2.4V, V_B=1.2V$	-20	20	
		$V_A=-1.4V, V_B=1.2V$	-32	0	
I_B	Input Current Receiver or Transceiver with Driver Disabled	$V_B=3.8V, V_A=1.2V$	0	32	μA
		$V_B=0V$ or $2.4V, V_A=1.2V$	-20	20	
		$V_B=-1.4V, V_A=1.2V$	-32	0	
I_{AB}	Differential Input Current Receiver or Transceiver with driver disabled (I_A-I_B); $V_A = V_B, -1.4 \leq V_A \leq 3.8V$	-4		4	μA
$I_{A(OFF)}$	Input Current Receiver or Transceiver Power Off $0V \leq V_{CC} \leq 1.5V$	$V_A=3.8V, V_B=1.2V$	0	32	μA
		$V_A=0V$ or $2.4V, V_B=1.2V$	-20	20	
		$V_A=-1.4V, V_B=1.2V$	-32	0	
$I_{B(OFF)}$	Input Current Receiver or Transceiver Power Off $0V \leq V_{CC} \leq 1.5V$	$V_B=3.8V, V_A=1.2V$	0	32	μA
		$V_B=0V$ or $2.4V, V_A=1.2V$	-20	20	
		$V_B=-1.4V, V_A=1.2V$	-32	0	
$I_{AB(OFF)}$	Receiver Input or Transceiver Input/Output Power Off Differential Input Current; (I_A-I_B) $V_A = V_B, 0 \leq V_{CC} \leq 1.5V, -1.4 \leq V_A \leq 3.8V$	-4		4	μA
C_A	Transceiver Input Capacitance with Driver Disabled $V_A = 0.4 \sin(30E^6\pi t) + 0.5V$ using HP4194A impedance analyzer (or equivalent); $V_B = 1.2V$		5		pF
C_B	Transceiver Input Capacitance with Driver Disabled $V_B = 0.4 \sin(30E^6\pi t) + 0.5V$ using HP4194A impedance analyzer (or equivalent); $V_A = 1.2V$		5		pF
C_{AB}	Transceiver Differential Input Capacitance with Driver Disabled $V_A = 0.4 \sin(30E^6\pi t) + 0.5V$ using HP4194A impedance analyzer (or equivalent); $V_B = 1.2V$			3.0	pF
$C_{A/B}$	Transceiver Input Capacitance Balance with Driver Disabled, (C_A/C_B)	99		101	%

Electrical Characteristics (Static) — continued

$V_{CC} = 3.3 \pm 10\% V$ (3.0 to 3.6V), $GND = 0 V$, $T_A = -40^\circ C$ to $+85^\circ C$ (See Notes 1, 2, 3)

ESD And Latch Up Performance					
Symbol	Parameter			Value	Unit
V _(ESD)	Electrostatic discharge	Human Body Model (JEDEC Standard 22, Method A114–A)	A, B	±8	kV
			All Other Pins	±4	
Latch Up Performance	JEDEC Standard No.78D			±200	mA

Note1: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfm.

Note2: See Figure 1. DC Measurements reference.

Note3: Typ value at $25^\circ C$ and 3.3V V_{CC} supply voltage

Electrical Characteristics (Dynamic)

$V_{CC} = 3.3 \pm 10\% V$ (3.0 to 3.6 V), $GND = 0 V$, $T_A = -40^\circ C$ to $+85^\circ C$ (Note 1,2)

Symbol	Parameter		Min	Typ	Max	Unit
Driver						
t _{PLH} /t _{PHL}	Propagation Delay (See Figure 5)		2.0	2.5	3.5	ns
t _{PHZ} /t _{PLZ}	Disable Time HIGH or LOW state to High Impedance (See Figure 6)				7	ns
t _{PZH} /t _{PZL}	Enable Time High Impedance to HIGH or LOW state (See Figure 6)				7	ns
t _{SK(P)}	Pulse Skew (t _{PLH} – t _{PHL}) (See Figure 5)				350	ps
t _{SK(PP)}	Device to Device Skew similar path and conditions (See Figure 5)				0.9	ns
t _{JIT(PER)}	Period Jitter RMS, 50 MHz (Source t _r /t _f 0.5 ns, 10 and 90 % points, 30k samples. Source jitter de-embedded from Output values) (See Figure 8)			2	3	ps
t _{JIT(PP)}	Peak-to-peak Jitter, 100 Mbps 2 ¹⁵ -1 PRBS (Source t _r /t _f 0.5 ns, 10 and 90% points, 100k samples. Source jitter de-embedded from Output values) (See Figure 8)			30	130	ps
t _r /t _f	Differential Output rise and fall times (See Figure 5)		0.5		1	ns
Receiver						
t _{PLH} /t _{PHL}	Propagation Delay (See Figure 10)		2	3.6	6	ns
t _{PHZ} /t _{PLZ}	Disable Time HIGH or LOW state to High Impedance (See Figure 11)				10	ns
t _{PZH} /t _{PZL}	Enable Time High Impedance to HIGH or LOW state (See Figure 11)				15	ns
t _{SK(P)}	Pulse Skew (t _{PLH} – t _{PHL}) (See Figure 10), C _L =15pF	Type1		100	300	ps
		Type2		500	850	
t _{SK(PP)}	Device to Device Skew similar path and conditions (See Figure 10) C _L =15pF				1	ns
t _{JIT(PER)}	Period Jitter RMS, 50 MHz (Source: V _{ID} = 200 mV _{PP} f V _{CM} = 1 V, t _r /t _f 0.5 ns, 10 and 90 % points, 30k samples. Source jitter de-embedded from Output values) (See Figure 12)			4	7	ps
t _{JIT(PP)}	Peak-to-peak Jitter, 100 Mbps 2 ¹⁵ -1 PRBS (Source t _r /t _f 0.5 ns, 10 and 90% points, 100k samples. Source jitter de-embedded from Output values) (See Figure 12)	Type1		200	700	ps
		Type2		225	800	
t _r /t _f	Differential Output rise and fall times (See Figure 12), C _L =15pF		2.3		3.5	ns

Note1: Device will meet the specifications after thermal equilibrium has been established when

mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfm.

Note2: Typ value at 25 °C and 3.3 V_{CC} supply voltage.

Parameter Measurement Information

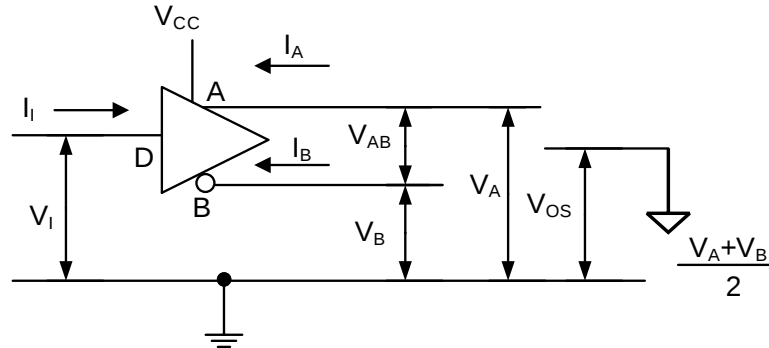
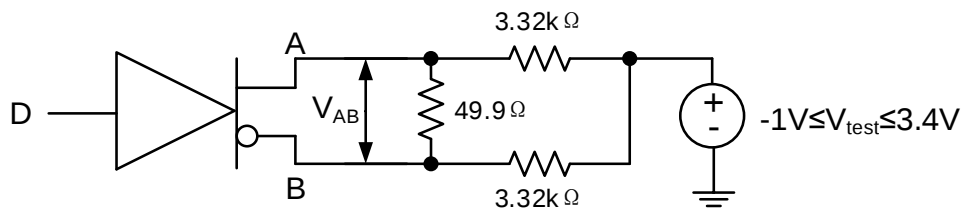
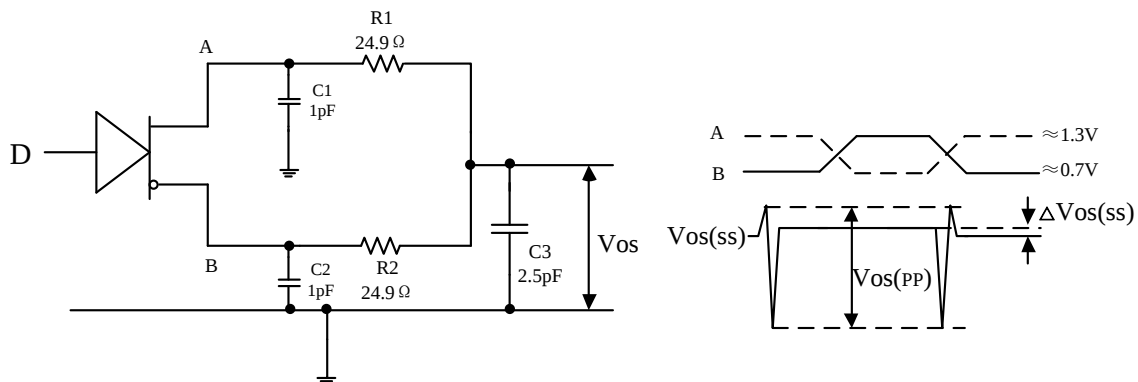


Figure 1. Driver Voltage and Current Definitions



Notes: A. All resistors are 1% tolerance.

Figure 2. Differential Output Voltage Test Circuit



Notes: A. All input pulses are supplied by a generator having the following characteristics:

t_r or $t_f \leq 1\text{ns}$, pulse frequency = 500 kHz, duty cycle = 50 ± 5%.

B. C1, C2 and C3 include instrumentation and fixture capacitance within 2 cm of the D.U.T. and are 20% tolerance.

C. R1 and R2 are metal film, surface mount, 1% tolerance, and located within 2 cm of the D.U.T.

D. The measurement of $V_{OS(pp)}$ is made on test equipment with a -3 dB bandwidth of at least 1 GHz.

Figure 3. Test Circuit and Definitions for the Driver Common-Mode Output Voltage

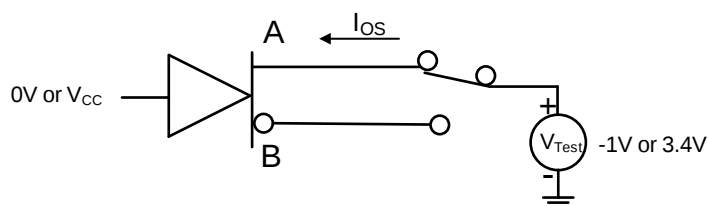
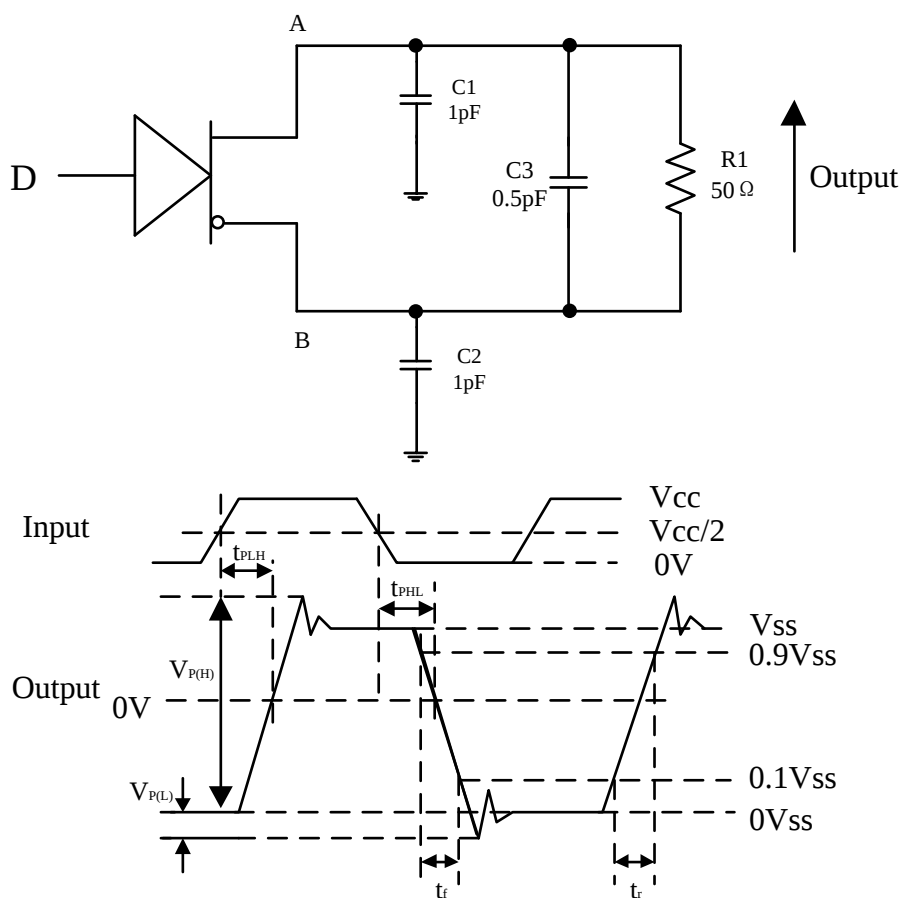
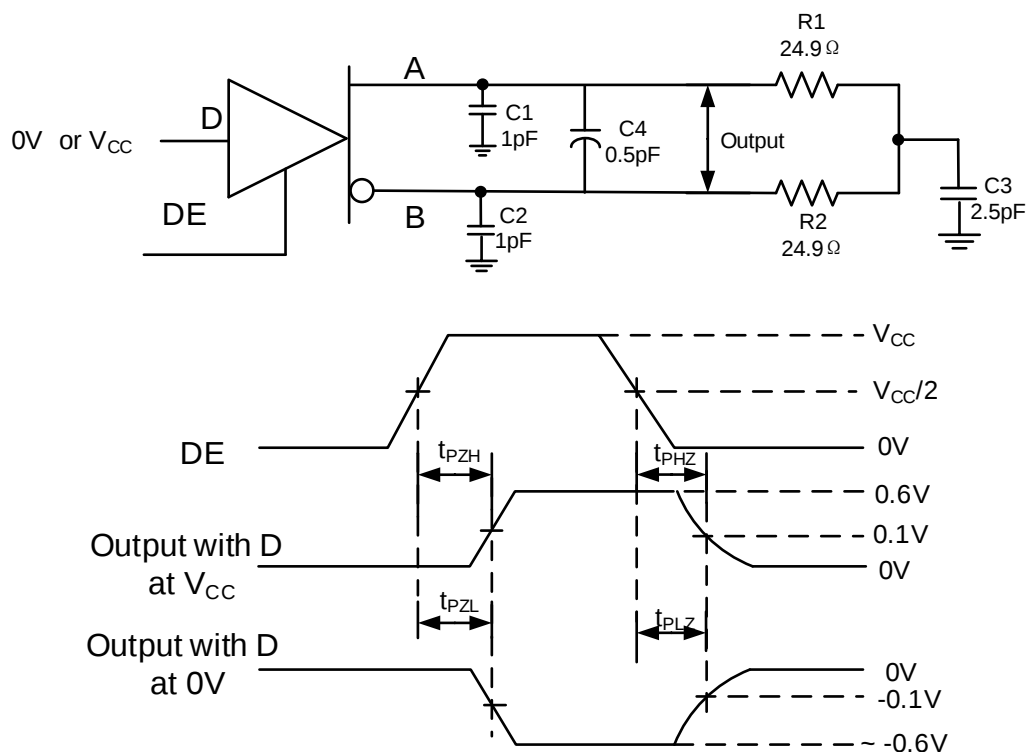


Figure 4. Driver Short-Circuit Test Circuit



- Notes:
- A. All input pulses are supplied by a generator having the following characteristics:
 t_r or $t_f \leq 1\text{ns}$, frequency = 500 kHz, duty cycle = $50 \pm 5\%$.
 - B. C1, C2 and C3 include instrumentation and fixture capacitance within 2 cm of the D.U.T. and are 20%.
 - C. R1 is a metal film, surface mount, and 1% tolerance and located within 2 cm of the D.U.T.
 - D. The measurement is made on test equipment with a -3 dB bandwidth of at least 1 GHz.

Figure 5. Driver Test Circuit, Timing, and Voltage Definitions for the Differential Output Signal



- Notes:
- A. All input pulses are supplied by a generator having the following characteristics:
 t_r or $t_f \leq 1\text{ns}$, frequency = 500 kHz, duty cycle = $50 \pm 5\%$.
 - B. C1, C2 and C3 include instrumentation and fixture capacitance within 2 cm of the D.U.T. and are 20%.
 - C. R1 and R2 are metal film, surface mount, and 1% tolerance and located within 2 cm of the D.U.T.
 - D. The measurement is made on test equipment with a -3 dB bandwidth of at least 1 GHz.

Figure 6. Driver Enable and Disable Time Circuit and Definitions

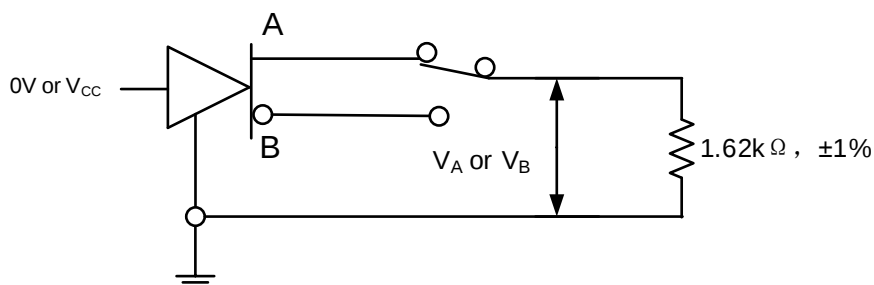
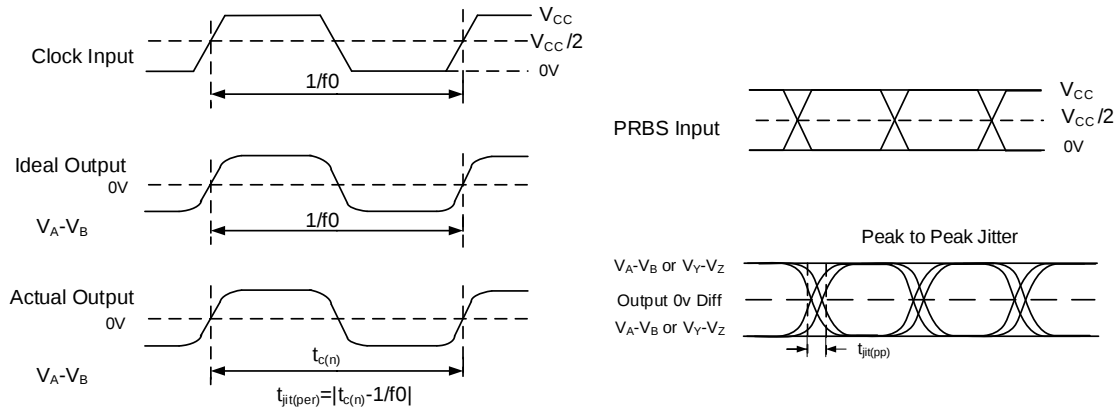


Figure 7. Maximum Steady State Output Voltage



- Notes:
- A. All input pulses are supplied by an Agilent 8304A Stimulus System.
 - B. The measurement is made on a TEK TDS6604 running TDSJIT3 application software
 - C. Period jitter is measured using a 50 MHz 50 $\pm 1\%$ duty cycle clock input.
 - D. Peak-to-peak jitter is measured using a 100 Mbps $2^{15}-1$ PRBS input.

Figure 8. Driver Jitter Measurement Waveforms

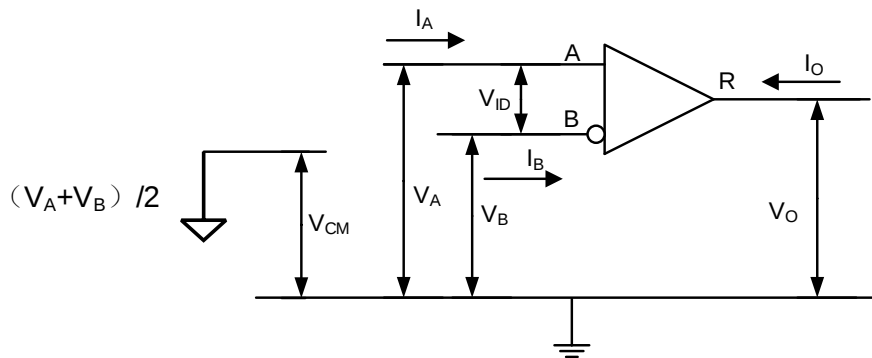
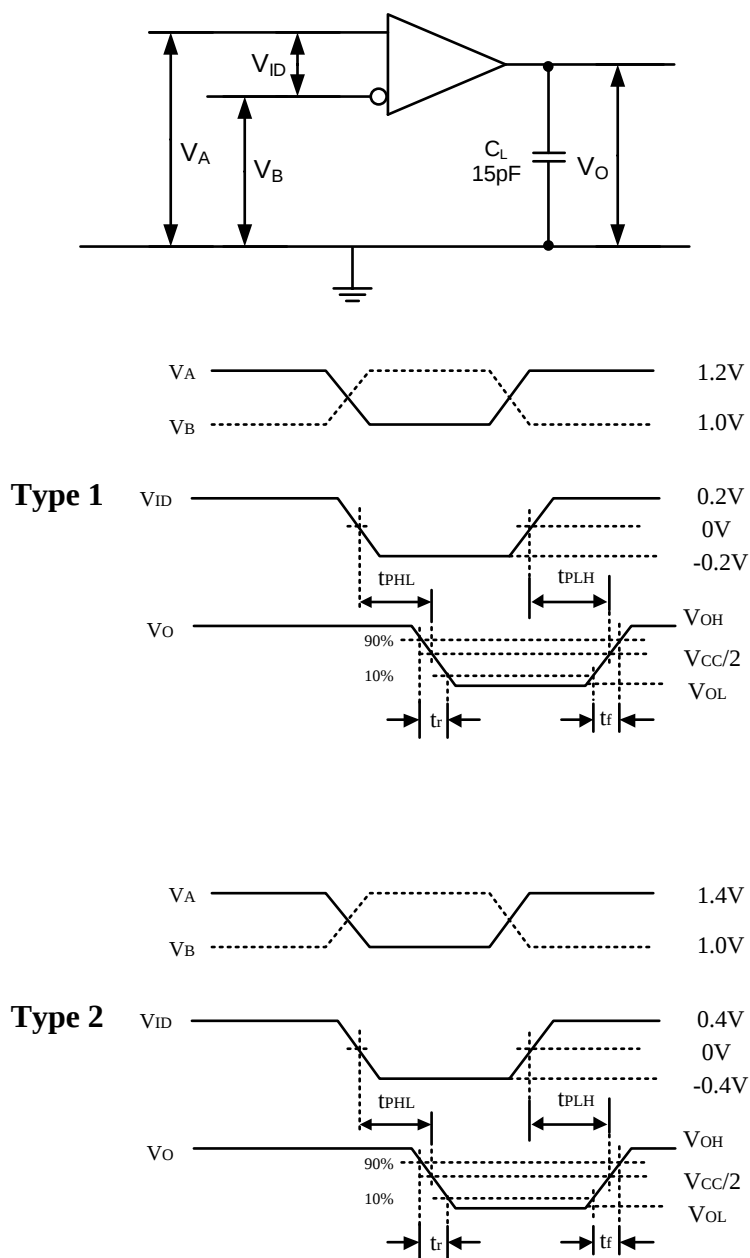
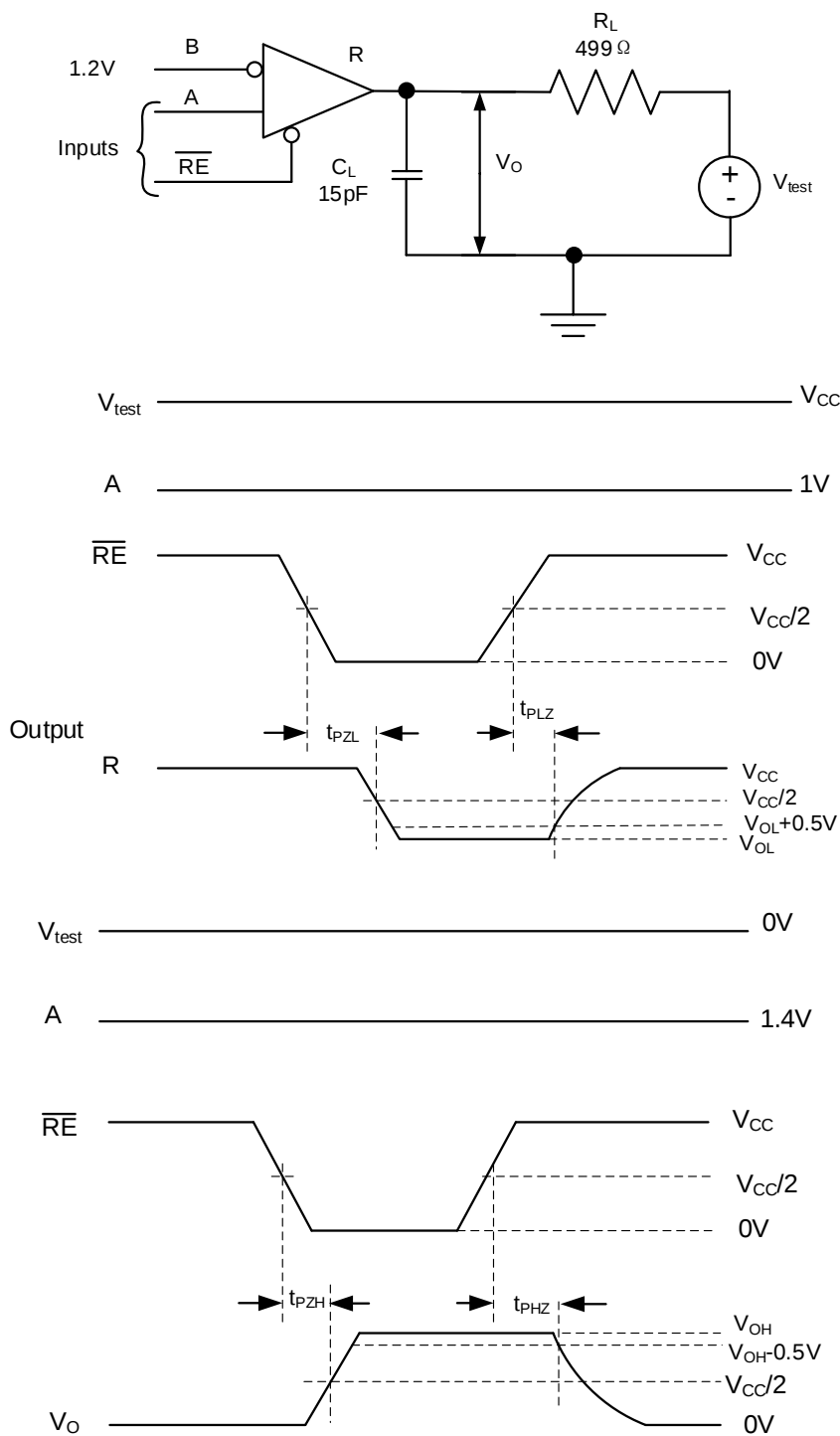


Figure 9. Receiver Voltage and Current Definitions



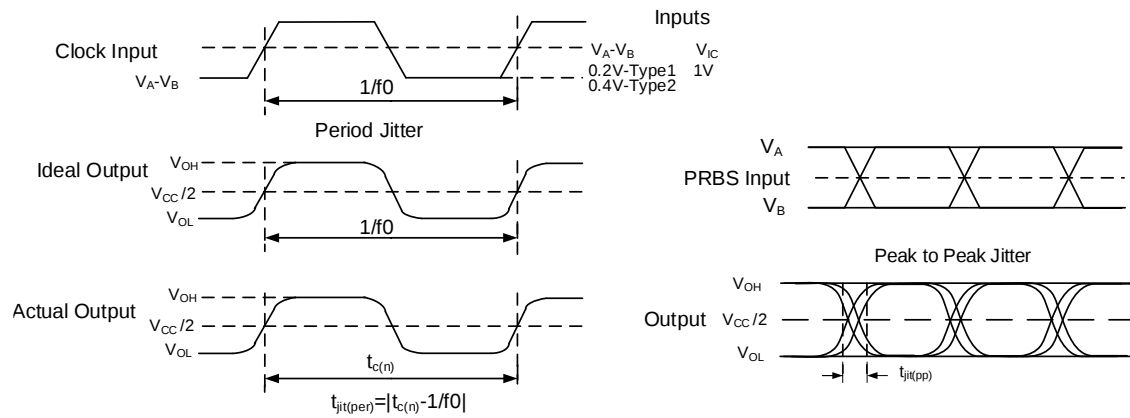
Notes: A. All input pulses are supplied by a generator having the following characteristics:
 t_r or $t_f \leq 1\text{ ns}$, frequency = 1 MHz , duty cycle = $50 \pm 5\%$. C_L is a combination of a 20%-tolerance, low-loss ceramic, surface-mount capacitor and fixture capacitance within 2 cm of the D.U.T.
 B. The measurement is made on test equipment with a -3 dB bandwidth of at least 1 GHz .

Figure 10. Receiver Timing Test Circuit and Waveforms



- Notes: A. All input pulses are supplied by a generator having the following characteristics:
 t_r or $t_f \leq 1$ ns, frequency = 500 kHz, duty cycle = $50 \pm 5\%$.
 B. R_L is 1% tolerance, metal film, surface mount, and located within 2 cm of the D.U.T.
 C. C_L is the instrumentation and fixture capacitance within 2 cm of the DUT and 20%.

Figure 11. Receiver Enable/Disable Time Test Circuit and Waveforms



- Notes:
- A. All input pulses are supplied by an Agilent 8304A Stimulus System.
 - B. The measurement is made on a TEK TDS6604 running TDSJIT3 application software
 - C. Period jitter is measured using a 50 MHz 50 $\pm$ 1% duty cycle clock input.
 - D. Peak-to-peak jitter is measured using a 100 Mbps $2^{15}-1$ PRBS input.

Figure 12. Receiver Jitter Measurement Waveforms

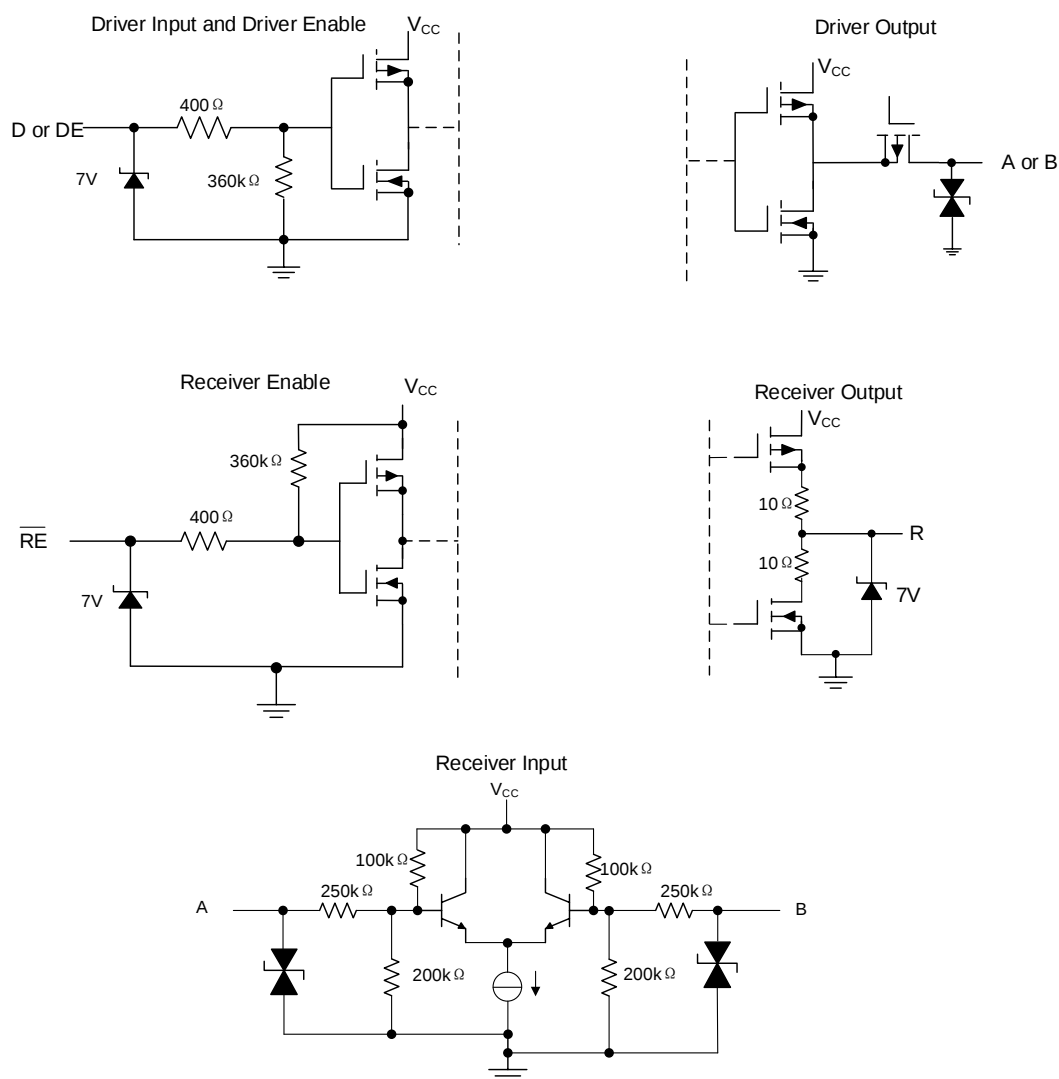


Figure 13. Equivalent Input and Output Schematic Diagrams

Table 1. Type1 Receiver Input Threshold Test Voltages

Applied Voltages		Resulting Differential Input Voltage	Resulting Common-Mode Input Voltage	Receiver Output (Note1)
V_{IA}	V_{IB}	V_{ID}	V_{IC}	
2.400	0.000	2.400	1.200	H
0.000	2.400	-2.400	1.200	L
3.425	3.375	0.050	3.400	H
3.375	3.425	-0.050	3.400	L
-0.975	-1.025	0.050	-1.000	H
-1.025	-0.975	-0.050	-1.000	L

Note1: H = High level, L = Low level, output state assumes receiver is enabled ($\overline{RE}=L$)

Table 2. Type2 Receiver Input Threshold Test Voltage

Applied Voltages		Resulting Differential Input Voltage	Resulting Common-Mode Input Voltage	Receiver Output (Note)
V _{IA}	V _{IB}	V _{ID}	V _{IC}	
2.400	0.000	2.400	1.200	H
0.000	2.400	-2.400	1.200	L
3.475	3.325	0.150	3.400	H
3.425	3.375	0.050	3.400	L
-0.925	-1.075	0.150	-1.000	H
-0.975	-1.025	0.050	-1.000	L

Note: H = High level, L = Low level, output state assumes receiver is enabled ($\overline{RE}=L$)

Device function

Table 3. Device function Table

Type 1 Receiver (UM3400)	Inputs		Output	
	V _{ID} = V _A - V _B	$\overline{RE}$	R	
	V _{ID} ≥ 50 mV	L	H	
	-50 mV < V _{ID} < 50 mV	L	?	
	V _{ID} ≤ -50 mV	L	L	
	X	H	Z	
	X	Open	Z	
	Open	L	?	
Type 2 Receiver (UM3401)	Inputs		Output	
	V _{ID} = V _A - V _B	$\overline{RE}$	R	
	V _{ID} ≥ 150 mV	L	H	
	50 mV < V _{ID} < 150 mV	L	?	
	V _{ID} ≤ 50 mV	L	L	
	X	H	Z	
	X	Open	Z	
	Open	L	L	
Driver	Input	Enable	Output	
	D	DE	A / Y	B / Z
	L	H	L	H
	H	H	H	L
	Open	H	L	H
	X	Open	Z	Z
	X	L	Z	Z

H = High, L = Low, Z = High Impedance, X = Don't Care, ? = Indeterminate

Applications Information

Receiver Input Threshold (Failsafe)

The MLVDS standard defines a type 1 and type 2 receiver. Type 1 receivers include no provisions for failsafe and have their differential input voltage thresholds near zero volts. Type 2 receivers have their differential input voltage thresholds offset from zero volts to detect the absence of a voltage difference. The impact to receiver output by the offset input can be seen in Table 3 and Figure 14.

Table 3. Receiver Input Threshold Requirements

Receiver Type	Output Low	Output High
Type 1	$-2.4\text{ V} \leq V_{ID} \leq -0.05\text{ V}$	$0.05\text{ V} \leq V_{ID} \leq 2.4\text{ V}$
Type 2	$-2.4\text{ V} \leq V_{ID} \leq 0.05\text{ V}$	$0.15\text{ V} \leq V_{ID} \leq 2.4\text{ V}$

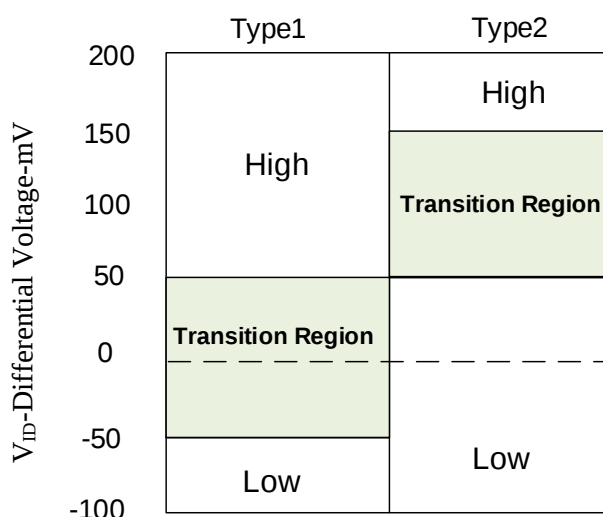


Figure 14. Receiver Differential Input Voltage Showing Transition Regions by Type

Live Insertion/Glitch-Free Power Up/Down

The UM3400/3401 provides a glitch-free power up/down feature that prevents the M-LVDS outputs of the device from turning on during a power up or power down event. This is especially important in live insertion applications, when a device is physically connected to an M-LVDS multipoint bus and V_{CC} is ramping. While the M-LVDS interface for these devices is glitch free on power up/down, the receiver output structure is not. The glitch on the R pin is independent of the RE voltage. Any complications or issues from this glitch are easily resolved in power sequencing or system requirements that suspend operation until V_{CC} has reached a steady state value.

Simplex Theory Configurations: Data flow is unidirectional and Point-to-Point from one Driver to one Receiver. UM3400 and UM3401 devices provide a high signal current allowing long drive runs and high noise immunity. Single terminated interconnects yield high amplitude levels. Parallel terminated interconnects yield typical MLVDS amplitude levels and minimizes reflections. See Figures 15 and 16. A UM3400 and UM3401 can be used as the driver or as a receiver.

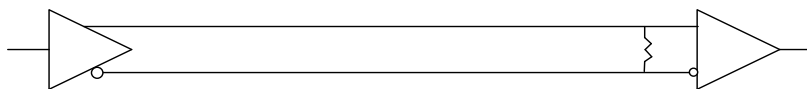


Figure 15. Point-to-Point Simplex Single Termination

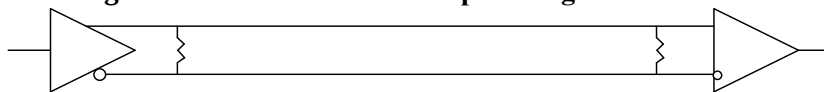


Figure 16. Parallel-Terminated Simplex

Simplex Multidrop Theory Configurations: Data flow is unidirectional from one Driver with one or more Receivers. Multiple boards required. Single terminated interconnects yield high amplitude levels. Parallel terminated interconnects yield typical MLVDS amplitude levels and minimizes reflections. On the Evaluation Test Board, Headers P1, P2, and P3 may be used as need to interconnect transceivers to each other or a bus. See Figures 20 and 21. A UM3400 and UM3401 can be used as the driver or as a receiver.

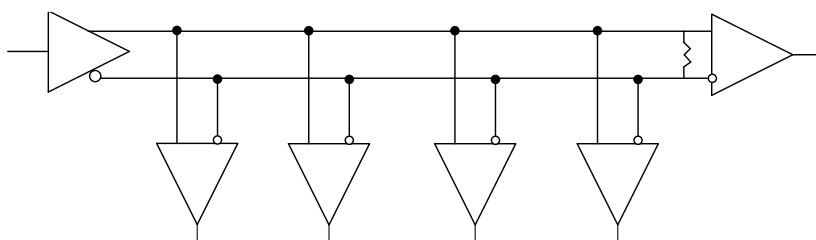


Figure 17. Multidrop or Distributed Simplex with Single Termination

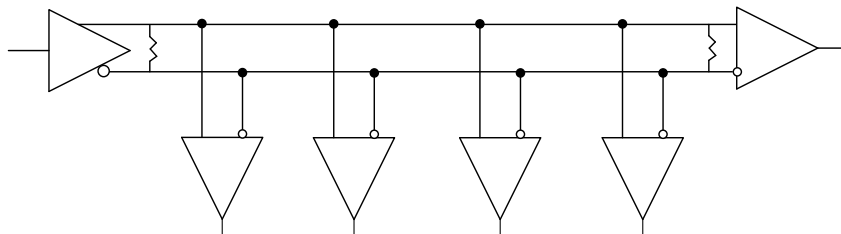


Figure 18. Multidrop or Distributed Simplex with Double Termination

Half Duplex Multinode Multipoint Theory Configurations: Data flow is unidirectional and selected from one of multiple possible Drivers to multiple Receivers. One “Two Node” multipoint connection can be accomplished with a single evaluation test board. More than Two Nodes requires multiple evaluation test boards. Parallel terminated interconnects yield typical MLVDS amplitude levels and minimizes reflections. Parallel terminated interconnects yield typical LMVDS amplitude levels and minimizes reflections. On the Test Board, Headers P1, P2, and P3 may be used as need to interconnect transceivers to each other or a bus. See Figure 19. A UM3401 can be used as the driver or as a receiver.

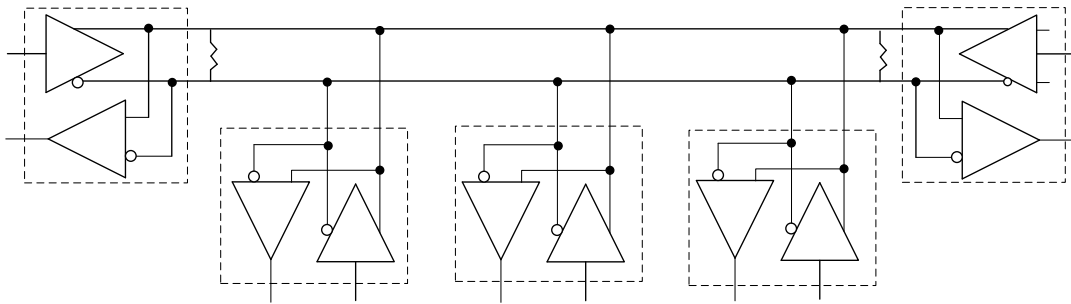
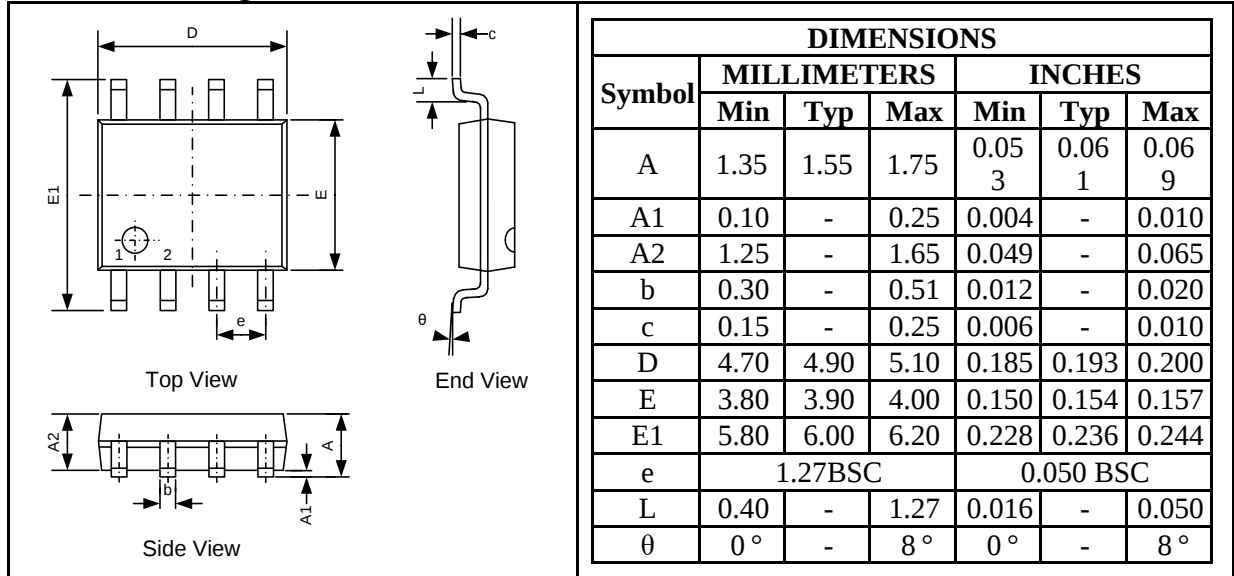


Figure 19. Multinode Multipoint Half Duplex (Requires Double Termination)

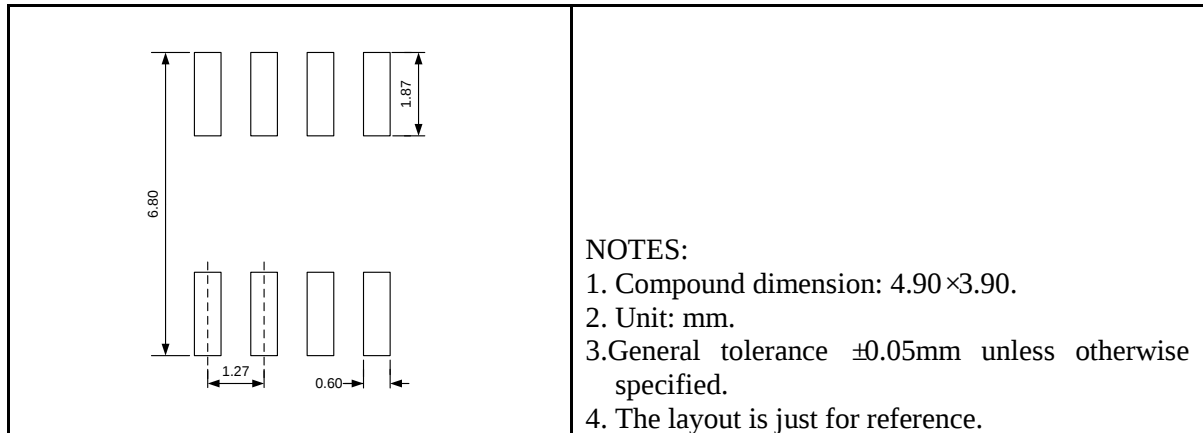
Package Information

UM3400 SOP8

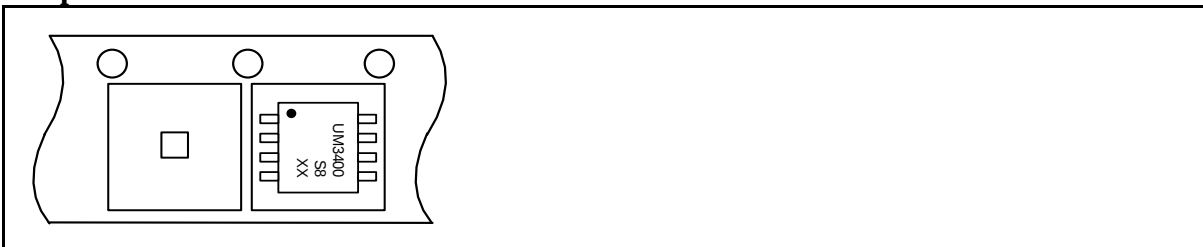
Outline Drawing



Land Pattern

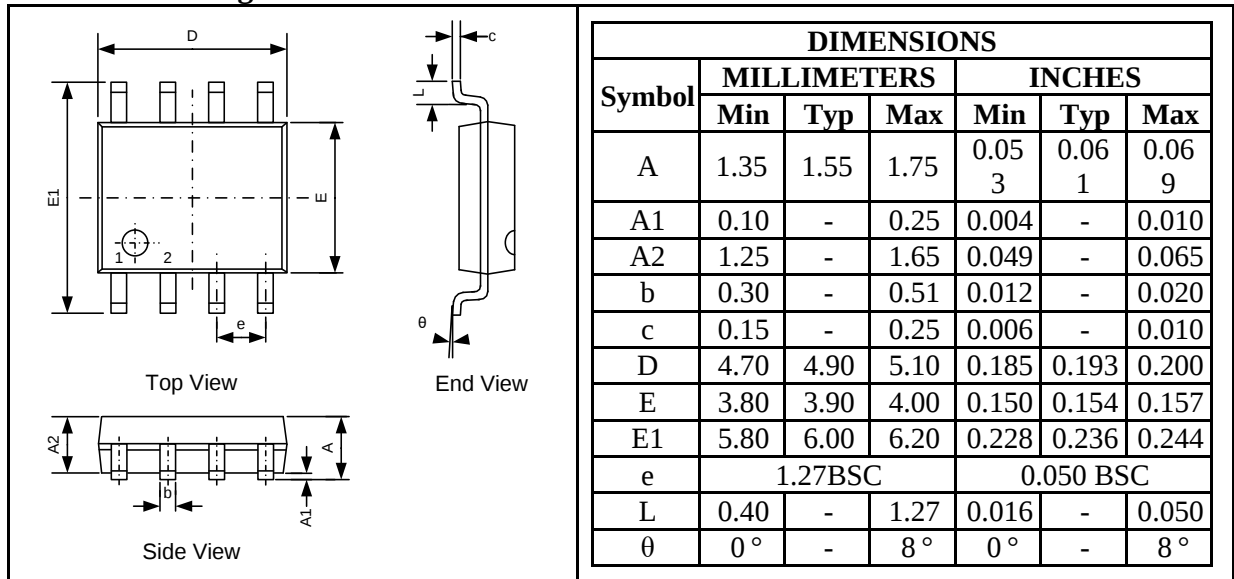


Tape and Reel Orientation

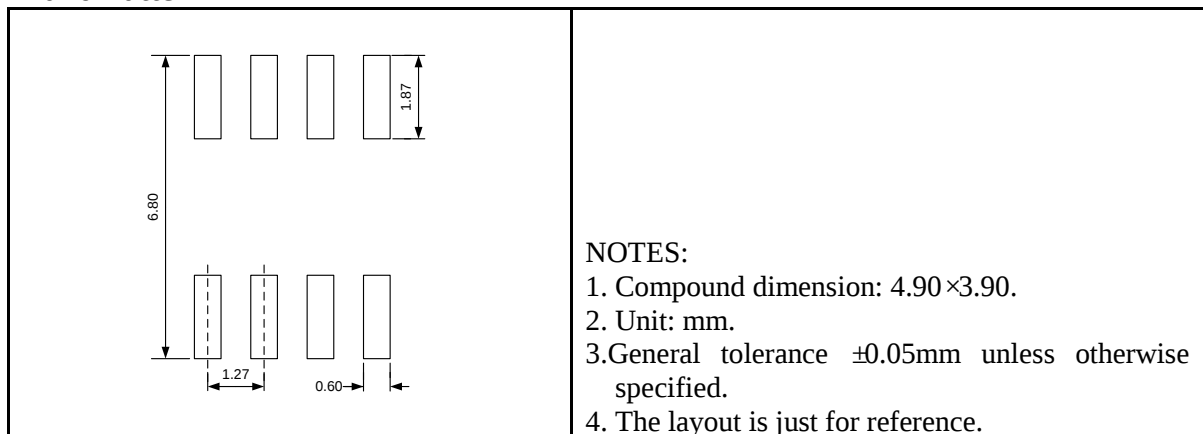


UM3401 SOP8

Outline Drawing



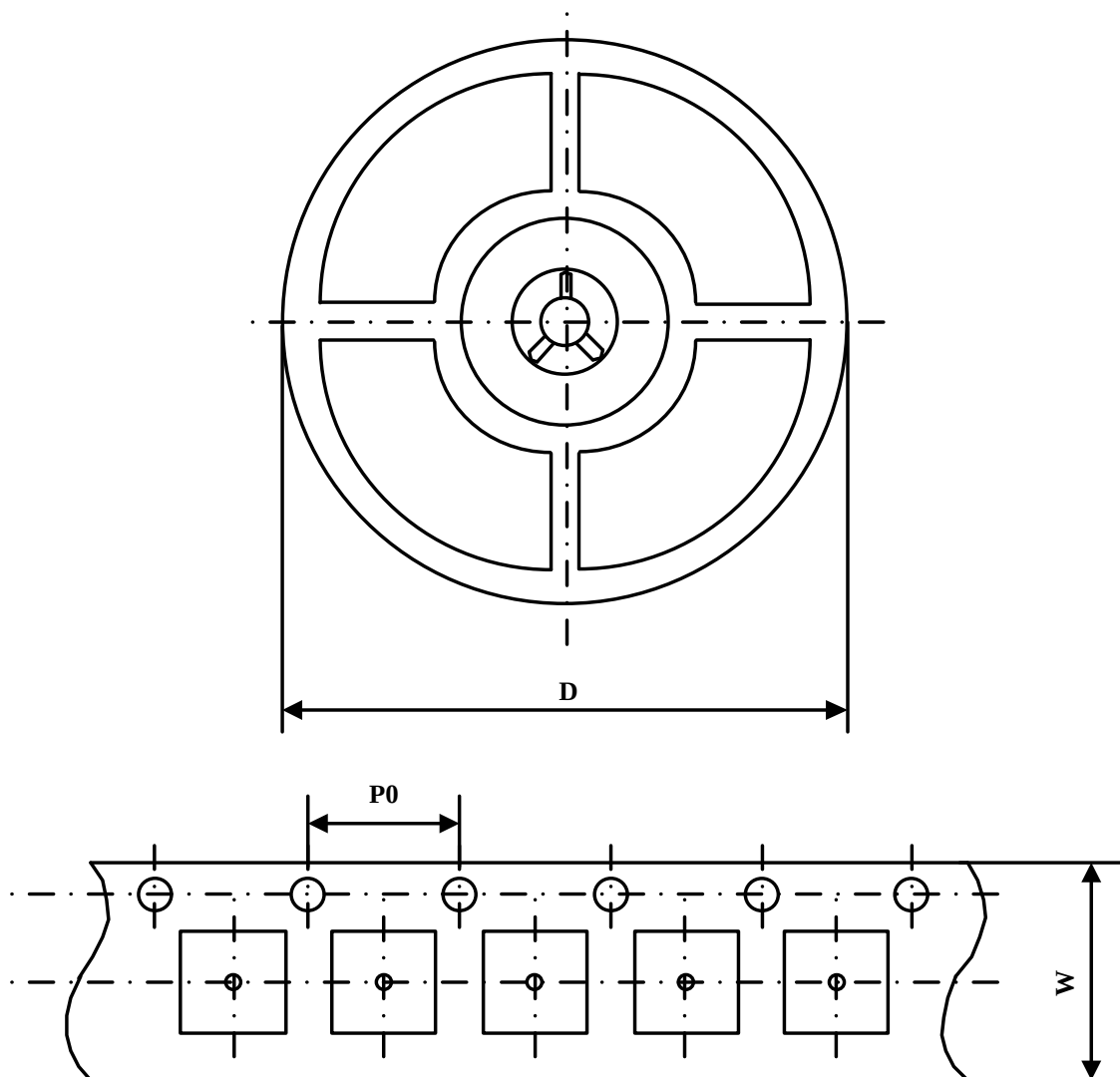
Land Pattern



Tape and Reel Orientation



Packing Information



Part Number	Package Type	Carrier Width(W)	Pitch(P0)	Reel Size(D)
UM400S8	SOP8	12 mm	4 mm	330 mm
UM3401S8	SOP8	12 mm	4 mm	330 mm

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